(11) Publication number:

0 180 222

A3

EUROPEAN PATENT APPLICATION

(21) Application number: 85113869.3

(22) Date of filing: 31.10.85

(5) Int.Cl.²: H 01 L 21/308 H 01 L 31/02, G 03 F 7/00

- 30 Priority: 01.11.84 JP 230812/84
- (43) Date of publication of application: 07.05.86 Bulletin 86/19
- (88) Date of deferred publication of search report: 12.10.88
- (84) Designated Contracting States: DE FR GB

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- (54) Surface roughening method.
- (57) A surface roughening method, preferably for a substrate of a solar cell, comprising coating the substrate with a photoresist material having light-shielding particles mixed therein, exposing and developing the photoresist coating and then etching the substrate with a suitable etchant.



EUROPEAN SEARCH REPORT

Application Number

EP 85 11 3869

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O PORM 1503 03.82 (PO401)

A: technological background
O: non-written disclosure
P: intermediate document

L: document cited for other reasons

& : member of the same patent family, corresponding document